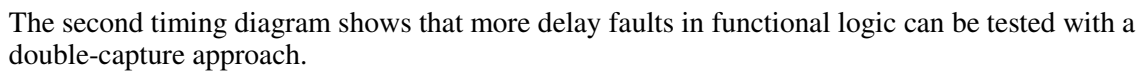


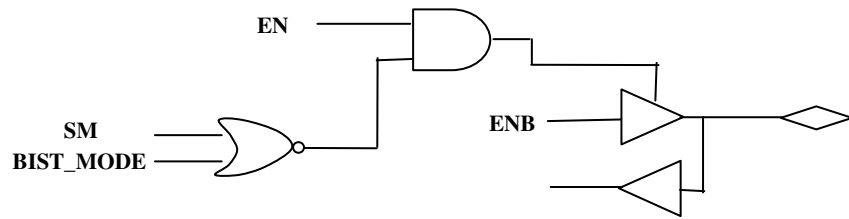
## 5.1



## 5.2



### 5.3 Reconfigure a bidirectional bus to input mode



### 5.4

To insert a zero state in each hybrid LFSR, an XOR gate is inserted into the last stage of the hybrid LFSR, and a NOR gate (with  $n-1$  inputs from the first  $n-1$  stages of LFSR) is used as a zero detector. For minimization in a standard CFSR, it can be done by Boolean minimization. For a modular CFSR, we can replace the XOR gate at the last stage of the CFSR with an OR gate and reconnect the tap to the OR-gate output. The period is 32.

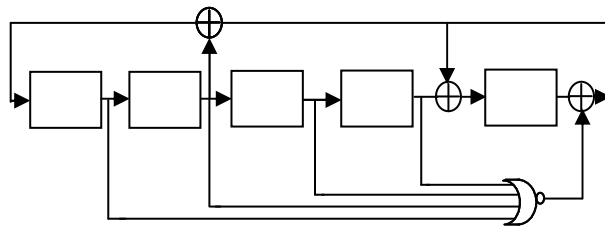


Figure 4a: Adding zero state into 5.13(a)

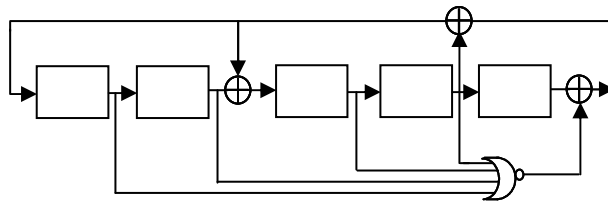
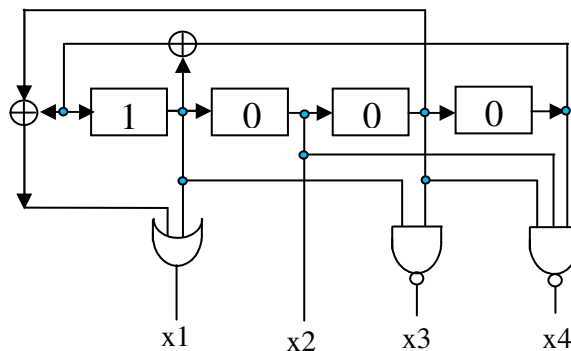


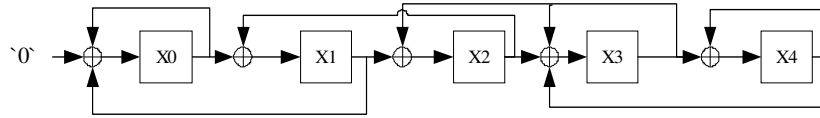
Figure 4b: Adding zero state into 5.13(b)

### 5.5



## 5.6

### 1) A 5-stage CA



The test sequence generated is:

00001	01001	00010	11110
00011	10111	00111	
00100	10110	01110	
01010	10101	11001	
10011	10001	01111	
11100	11011	11010	
00110	01000	01011	
01101	10100	10000	
11101	10010	11000	
00101	11111	01100	

From the above sequence, we can find the 5-stage CA generates a maximum-length of 31 distinct states.

### 2)

One of the construction rules for cellular automata of length 54 is 404,121,000,146,677,141.

One of the construction rules for cellular automata of length 55 is 1,204,121,000,146,676,412.

## 5.7

For  $(n,w) = (8,3)$  compute the smallest integer  $k$  such that  $w < [k/(n-k+1)] + [k/(n-k+2)]$  that is  $3 < [k/(9-k)] + [k/(9-k-1)]$ , then  $k = 6$ . The primitive polynomial of degree 6 is  $1+x+x^6$  using  $f(x) = g(x)p(x) = (1+x+x^2)(1+x+x^6) = 1+x^3+x^6+x^7+x^8$ .

Comparison with the (8,5) cyclic LFSR given in Figure 6.15:

	Number of XOR Gates	Test Length
(8,3) Condensed LFSR	3	63
(8,5) Cyclic LFSR	3	31

## 5.8

Given the (15,5) cyclic LFSR with  $g(x) = (1+x)(1+x+x^4) = 1+x^2+x^4+x^5$ ,  $h(x) = (1+x^{15})/g(x) = 1+x^2+x^3+x^6+x^8+x^9+x^{10}$ ,  $p(x) = 1+x^2+x^3+x^4+x^5$ , and  $f(x) = h(x)p(x) = 1+x^3+x^5+x^8+x^9+x^{11}+x^{12}+x^{13}+x^{15}$ . Figure 1 shows the (15,5) LFSR with  $S_0(x) = h(x) = <101001101110000>$ . It uses seven XOR gates.

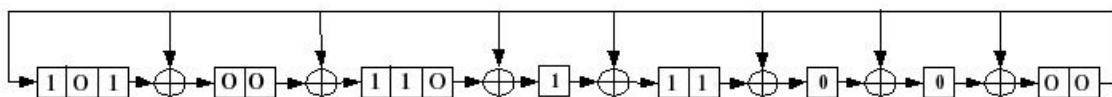


Figure 8: A (15,5) LFSR

In order to get (8,5) cyclic LFSR from (15,5) cyclic LFSR, let's pick the first 6 stages and the last 2 stages of the (15,5) cyclic LFSR that uses the least number of XOR gates. Then try to find the inputs necessary to produce the present state,  $x_i(t)$ , or the next state,  $x_i(t+1)$ , of the shortened (8, 5) LFSR with the same initial state.

1. Find the next state of the (8,5) LFSR from the (15,5) LFSR. From  $f(x)$  and Figure 1, we know that  $x_{13}(t+1) = x_{12}(t) + x_{14}(t)$ .
2. Find the present state of the (8,5) LFSR from the (15,5) LFSR.  
Matrix  $H$  below is a generator matrix of the cyclic code generated by  $h(x)$ . The  $H$  matrix is formed by using  $h(x) = 1+x^2+x^5+x^6+x^8+x^9+x^{10}$ .

$$H = \begin{bmatrix} x_0 & x_1 & x_2 & x_3 & x_4 & x_5 & x_6 & x_7 & x_8 & x_9 & x_{10} & x_{11} & x_{12} & x_{13} & x_{14} \\ 1 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 & 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 \end{bmatrix}$$

It has a rank  $k = 5$ . Let  $x_i$  ( $i = 1, 2, \dots, 14$ ) denote the  $i^{\text{th}}$  column of matrix  $H$ . From matrix  $H$ , we know that  $x_{13}(t+1) = x_{12}(t) + x_{14}(t) = x_5(t) + x_2(t)$ . So, the (8, 5) cyclic LFSR is obtained as shown in Figure 2.

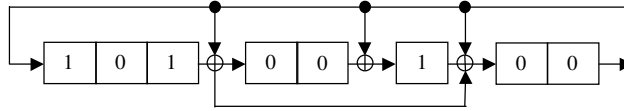


Figure 8: The (8,5) cyclic LFSR shortened from (15,5) cyclic LFSR

## 5.9

According to the question the cyclic LFSR (15,5) can be built by  $g(x) = (1+x)(1+x+x^4) = 1+x^2+x^4+x^5$ ,  $h(x) = (1+x^{15})/g(x) = 1+x^2+x^5+x^6+x^8+x^9+x^{10}$ . Then, a 5-by-15 matrix  $H$  can be generated by  $h(x)$ :

$$H = \begin{bmatrix} x_0 & x_1 & x_2 & x_3 & x_4 & x_5 & x_6 & x_7 & x_8 & x_9 & x_{10} & x_{11} & x_{12} & x_{13} & x_{14} \\ 1 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 & 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 \end{bmatrix}$$

and matrix  $H'$  can be generated by applying elementary row manipulation on  $H$  such that the first  $k$  columns of the resulting matrix  $H'$  form a 5-by-5 identity matrix:

$$H' = \begin{bmatrix} x0 & x1 & x2 & x3 & x4 & x5 & x6 & x7 & x8 & x9 & x10 & x11 & x12 & x13 & x14 \\ 1 & 0 & 0 & 0 & 0 & 1 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 \\ 0 & 1 & 0 & 0 & 0 & 1 & 1 & 1 & 1 & 0 & 1 & 0 & 1 & 1 & 0 \\ 0 & 0 & 1 & 0 & 0 & 0 & 1 & 1 & 1 & 1 & 0 & 1 & 0 & 1 & 1 \\ 0 & 0 & 0 & 1 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 & 0 \\ 0 & 0 & 0 & 0 & 1 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 \end{bmatrix}$$

In matrix  $H'$ , there are 8 zeros in the first row  $\langle x1, x2, x3, x4, x6, x8, x9, x12 \rangle$ . It means that they are linear independent with  $x0$ . Then, a 4-by-14 matrix  $H''$  can be formed by simply removing the first row and first column in matrix  $H'$ :

$$H'' = \begin{bmatrix} & x1 & x2 & x3 & x4 & x5 & x6 & x7 & x8 & x9 & x10 & x11 & x12 & x13 & x14 \\ 1 & 0 & 0 & 0 & 1 & 1 & 1 & 1 & 0 & 1 & 0 & 1 & 1 & 1 & 0 \\ 0 & 1 & 0 & 0 & 0 & 1 & 1 & 1 & 1 & 0 & 1 & 0 & 1 & 1 & 1 \\ 0 & 0 & 1 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 & 1 & 0 \\ 0 & 0 & 0 & 1 & 0 & 1 & 0 & 0 & 1 & 1 & 0 & 1 & 1 & 1 & 1 \end{bmatrix}$$

In order to avoid the loss of linear independence, matrix  $M$  can be formed by selecting  $\langle x1, x2, x3, x4, x6, x8, x9, x12 \rangle$ :

$$M = \begin{bmatrix} x1 & x2 & x3 & x4 & x6 & x8 & x9 & x12 \\ 1 & 0 & 0 & 0 & 1 & 1 & 0 & 1 \\ 0 & 1 & 0 & 0 & 1 & 1 & 1 & 0 \\ 0 & 0 & 1 & 0 & 0 & 1 & 1 & 1 \\ 0 & 0 & 0 & 1 & 1 & 0 & 1 & 1 \end{bmatrix}$$

Build a (14,4) LFSR by using  $f(x)=h(x)p(x)$ , where  $p(x)$  is the primitive polynomial of degree 4. Then, by using  $f(x)=h(x)p(x) = (1+x^2+x^3+x^6+x^8+x^9+x^{10})(1+x+x^4) = 1+x^2+x^3+x^4+x^5+x^6+x^7+x^8+x^{10}+x^{11}+x^{12}+x^{13}+x^{14}$ , an (8,4) LFSR can be obtained by choosing the 8 stages of  $\langle x1, x2, x3, x4, x6, x8, x9, x12 \rangle$  of the (14,4) LFSR. Let  $V_i(t)$  and  $V_i(t+1)$  denote the present state and next states of stage  $V_i$  of the (14,4) LFSR respectively. Only those discontinuities in the eight columns must be replicated in order to preserve the shortened cyclic code properly. These discontinuities are the present state of  $V_{14}$ , and the next state of  $V_6, V_8$  and  $V_{12}$ . They can be obtained from the (14,4) LFSR with  $V_{14}(t) = V_8(t)+V_{12}(t)$ ;  $V_6(t+1) = V_4(t)+V_8(t)$ ;  $V_8(t+1) = V_2(t)+V_6(t)$ ;  $V_{12}(t+1) = V_2(t)+V_9(t)$ . Fig. 9(a) shows a (14,4) LFSR with  $S_0(x) = h(x) = \langle 10100110111000 \rangle$ , and Fig. 9(b) shows an (8,4) LFSR obtained from the (14,4) LFSR.

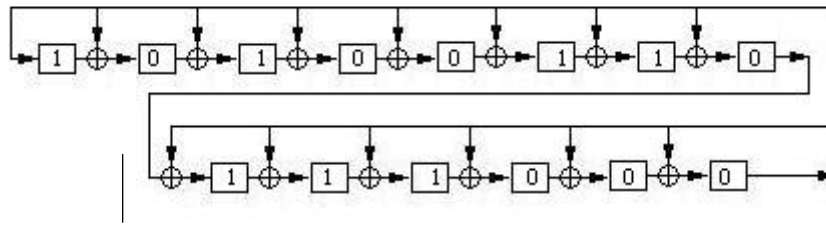


Figure 9(a): A (14,4) LFSR

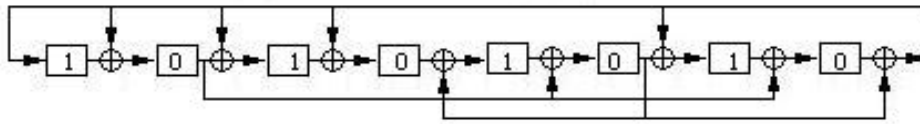
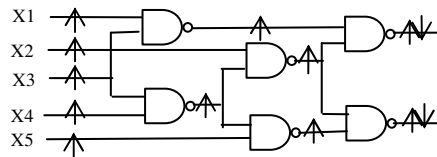


Figure 9(b): An (8,4) LFSR

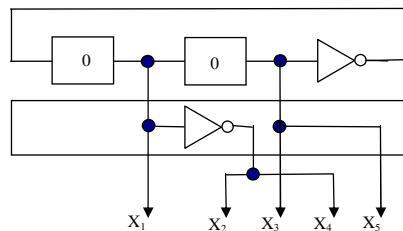
### 5.10

All collapsed single stuck-at faults in Figure 5.25(a) have been shown in the following figure:

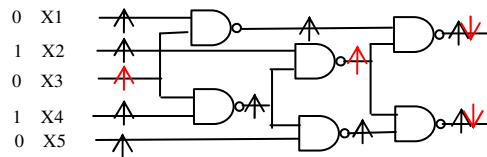


(a)  $An(n, w) = (5, 4)$  CUT

Pattern Generate in the structure of 5.25(b)

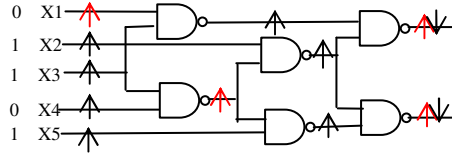


Faults detected by test pattern  $(X_1, X_3) = \{00\}$  given below are marked by red color:



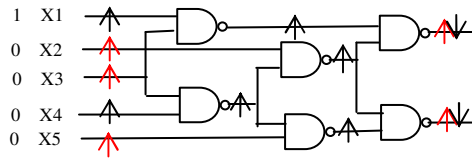
(b)  $An(n, w) = (5, 4)$  CUT

Faults detected by test pattern  $(X_1, X_3) = \{01\}$  given below are marked by red color:



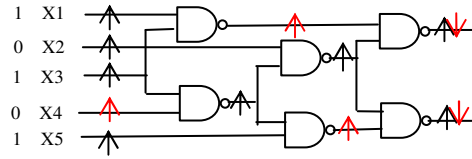
(c)  $An(n, w) = (5, 4)$  CUT

Faults detected by test pattern  $(X_1, X_3) = \{10\}$  given below are marked by red color:



(d)  $An(n, w) = (5, 4)$  CUT

Faults detected by test pattern  $(X_1, X_3) = \{11\}$  given below are marked by red color:



(e)  $An(n, w) = (5, 4)$  CUT

## 5.11

Given  $R_0 = \{01101111\}$  and  $R_1 = \{00110001\}$ :

When using ones count testing, we obtain  $OC(R_0) = 6$  and  $OC(R_1) = 3$ . Because  $OC(R_0) \neq OC(R_1)$ , this fault can be detected. The aliasing probability is:

$$P_{OC}(6) = (C(8, 6) - 1) / (2^8 - 1) = 27 / 255 = 0.11$$

When using transition count testing, we obtain  $TC(R_0) = 3$  and  $TC(R_1) = 3$ . Because  $TC(R_0) = TC(R_1)$ , this fault cannot be detected. The aliasing probability is:

$$P_{TC}(3) = (2C(7, 3) - 1) / (2^8 - 1) = 69 / 255 = 0.27$$

### 5.12

Given  $f(x) = 1 + x + x^4$  and  $M = \{10011011\}$ , we obtain the fault-free signature  $R = \{1011\}$ . For the faulty sequence  $M' = \{11111111\}$  or  $M'(x) = 1 + x + x^2 + x^3 + x^4 + x^5 + x^6 + x^7$ , by polynomial division  $M'(x) = q'(x)f(x) + r'(x)$ , we can obtain  $q'(x) = x + x^2 + x^3$ , and  $r'(x) = 1 + x^2 + x^3$ . Thus, the faulty signature  $R' = \{1011\}$ . Since  $R' = R$ , the fault is undetected.

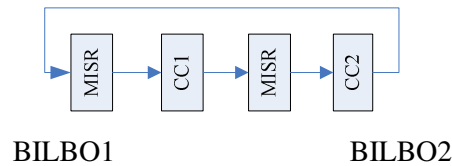
Another solution can be deduced by using error sequence  $E$  where  $E = M + M' = \{01100100\}$  or  $E(x) = x + x^2 + x^5$ . By polynomial division, we obtain  $E(x) = xf(x)$ . Since  $f(x)$  divides  $E(x)$ , this fault is undetected.

### 5.13

Given  $M_0' = \{00010\}$ ,  $M_1' = \{00010\}$ ,  $M_2' = \{11100\}$ , and  $M_3' = \{10000\}$ . By  $M'(x) = M_0'(x) + xM_1'(x) + x^2M_2'(x) + x^3M_3'(x)$ , we have  $M' = \{00110000\}$  or  $M'(x) = x^2 + x^3$ . The faulty signature  $R' = \{0011\}$ . For  $M = \{10011011\}$  and fault-free signature  $R = \{1011\}$ , because  $R' \neq R$ , this fault is detected.

### 5.14

1. To test a pipelined-oriented circuit using BILBOs

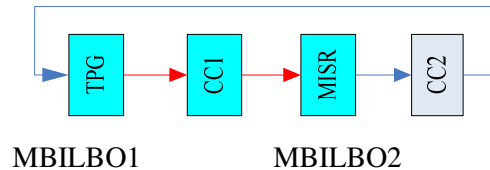


As one can see, using BILBOs, the signature data from the previous module must be used as test patterns for the next module, since the test generation and signature analysis modes cannot be separated. If  $n$  vectors are used to test the circuit, the test time required would be  $n$  clock cycles. In this case, a detailed fault simulation is required to achieve 100% single-stuck fault coverage.

2. To test a pipelined-oriented circuit using MBILBOs

Because test generation and signature analysis are separated from each other in time but not in space,  $CCI$  and  $CC2$  can be tested alternatively.

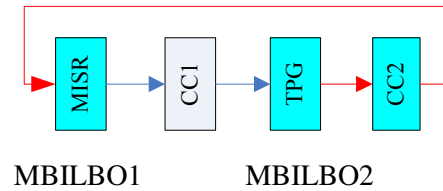
Step 1:



Now, suppose  $CCI$  is to be tested. MBILBO1 will be reconfigured as a PRPG by setting  $B1 = 1$ ,  $B2 = 0$ , and  $B3 = 1$ . Meanwhile, MBILBO2 will be reconfigured as a MISR by setting  $B1 = 1$ ,  $B2 = 0$ , and  $B3 = 0$ . During this time,  $CC2$  is not tested.



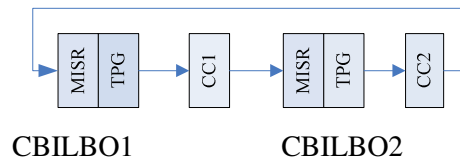
Step 2:



Now, suppose *CC2* is to be tested. By reconfiguring MBILBO1 and MBILBO2 as MISR and TPG, respectively, *CC2* can be tested exhaustively or pseudo-exhaustively. During this time, *CC1* is not tested. According to the above analysis, we can conclude that if  $n$  vectors can be used to test each module exhaustively or pseudo-exhaustively, then total test time may become  $2n$  clock cycles. In this case, a detailed fault simulation is not required.

### 3. To test a pipelined-oriented circuit using CBILBOs

Because test generation and signature analysis are separated from each other both in time and space with using two storage elements in each CBILBO, it is possible to test both *CC1* and *CC2* simultaneously. In addition, no fault simulation will be required to achieve 100% single-stuck fault coverage if exhaustive or pseudo-exhaustive patterns are used. Therefore,  $n$  clock cycles are only needed.



The following table shows the advantages and disadvantages of using the BILBO, MBILBO, and CBILBO approaches:

	Hard cost	Test time	Fault coverage
BILBO	Low	Short	Low
MBILBO	Medium	Long	High
CBILBO	High	Short	High

## 5.15

(1) When both shift and capture at 200MHz:

STUMPS:

$$\text{Test time} = [100000 \times 1000 + 100000] \times (1/200\text{M}) = 0.5005\text{s}$$

BILBO:

$$\text{Test time} = 100000 \times (1/200\text{M}) + 2 \times 1000 \times 100 \times (1/200\text{M}) = 1.5\text{ms}$$

(2) When shift at 20MHz and capture at 200MHz

STUMPS:

$$\text{Test time} = 100000 \times 1000 \times (1/20\text{M}) + 100000 \times (1/200\text{M}) = 5.005\text{s}$$

(3) The main reason why the STUMPS-based architecture is gaining more popularity than the BILBO-based architecture is because STUMPS can be implemented with the conventional scan architecture, without adding additional logic to the scan chains. Also, the hardware cost is low.

## 5.16

(1) Before inserting test point:

For the stuck-at-0 fault present at  $X_3$ , all inputs of the AND gate,  $X_1$ ,  $X_2$ ,  $X_3$ ,  $X_4$ ,  $X_5$  and  $X_6$ , need to be 1. We need a 1 at  $X_3$  to activate the stuck-at-0 fault and a 1 for each other input to propagate the faults. So the detection probability of a stuck-at-0 fault at  $X_3$  is  $1/64$  ( $= 1/2 * 1/2 * 1/2 * 1/2 * 1/2 * 1/2$ ).

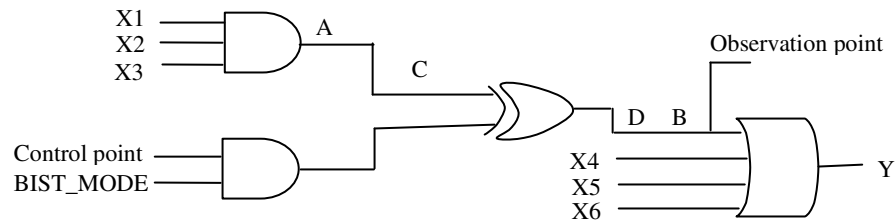
For the stuck-at-1 fault present at  $X_6$ , input  $X_6$  needs to be 0 to activate the fault, and all other inputs of the AND gate,  $X_1$ ,  $X_2$ ,  $X_3$ ,  $X_4$ , and  $X_5$ , must be set to 1 to propagate the fault. So the detection probability of stuck-at-one fault at  $X_6$  is  $1/64$  ( $= 1/2 * 1/2 * 1/2 * 1/2 * 1/2 * 1/2$ ).

(2) After inserting test point:

For the stuck-at-0 fault present at  $X_3$ , input  $X_3$  needs to be 1 to activate the fault. Inputs  $X_1$  and  $X_2$  need to be 1 and the control point needs to be 0 to propagate the fault. So the detection probability of the stuck-at-0 fault at  $X_3$  is  $1/16$  ( $= 1/2 * 1/2 * 1/2 * 1/2$ ).

For the stuck-at-1 fault present at  $X_6$ , input  $X_6$  needs to be 0 to activate the fault. Assume that another input of the OR gate (with control point) is A, and the OR gate output is B. To propagate the stuck-at-1 at  $X_6$ , Inputs  $X_4$ ,  $X_5$ , and B must be set to 1. Thus, either A or the control point need to be 1. The probability of 1 at B is  $9/16$  ( $= 1 - 7/8 * 1/2$ ). So the detection probability of the stuck-at-one fault at  $X_6$  is  $9/128$  ( $= 9/16 * 1/2 * 1/2 * 1/2$ ).

## 5.17



The test point added is presented in figure above. The 0/1 probability of nodes is presented below:

	$X_1$	$X_2$	$X_3$	A	C	Control point	D	B	$X_4$	$X_5$	$X_6$	Y
P1	1/2	1/2	1/2	1/8	1/8	1/2	1/2	1/2	1/2	1/2	1/2	15/16
P0	1/2	1/2	1/2	7/8	7/8	1/2	1/2	1/2	1/2	1/2	1/2	1/16

The detection probability of each fault is:

Stuck-at-1 at  $X_1$ ,  $X_2$  and  $X_3$  is  $1/16$  ( $= 1/8 * 1/2$ )

Stuck-at-0 at  $X_1$ ,  $X_2$  and  $X_3$  is  $1/16$  ( $= 1/8 * 1/2$ )

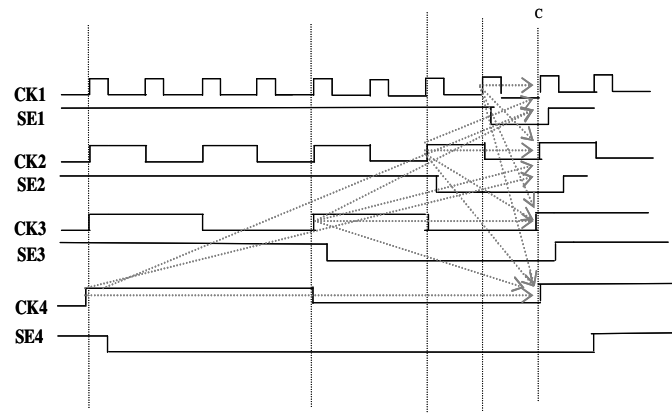
Stuck-at-1 at A and C is  $7/16$  ( $= 7/8 * 1/2$ )

Stuck-at-0 at A and C is  $1/16 (=1/8*1/2)$   
 Stuck-at-1 at D is  $1/2$   
 Stuck-at-0 at D is  $1/2$   
 Stuck-at-1 at B is  $1/16 (=1/2*1/2*1/2*1/2)$   
 Stuck-at-0 at B is  $1/16 (=1/2*1/2*1/2*1/2)$   
 Stuck-at-1 at  $X_4, X_5$  and  $X_6$  is  $1/16 (=1/2*1/2*1/2*1/2)$   
 Stuck-at-0 at  $X_4, X_5$  and  $X_6$  is  $1/16 (=1/2*1/2*1/2*1/2)$   
 Stuck-at-1 at Y is  $1/16$   
 Stuck-at-0 at Y is  $15/16$

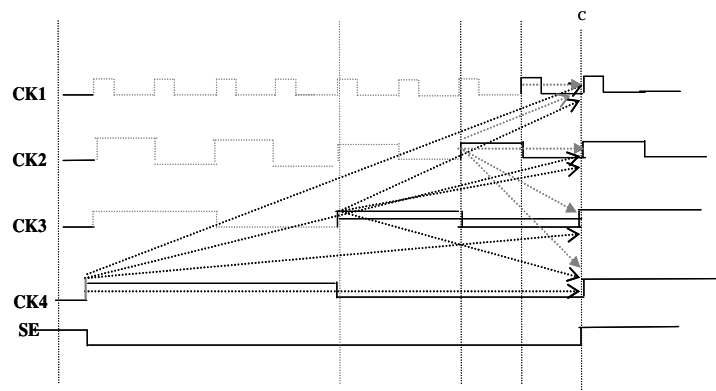
The detection probabilities are all greater than or equal to  $1/16$ .

## 5.18

Aligned skewed-load in capture:

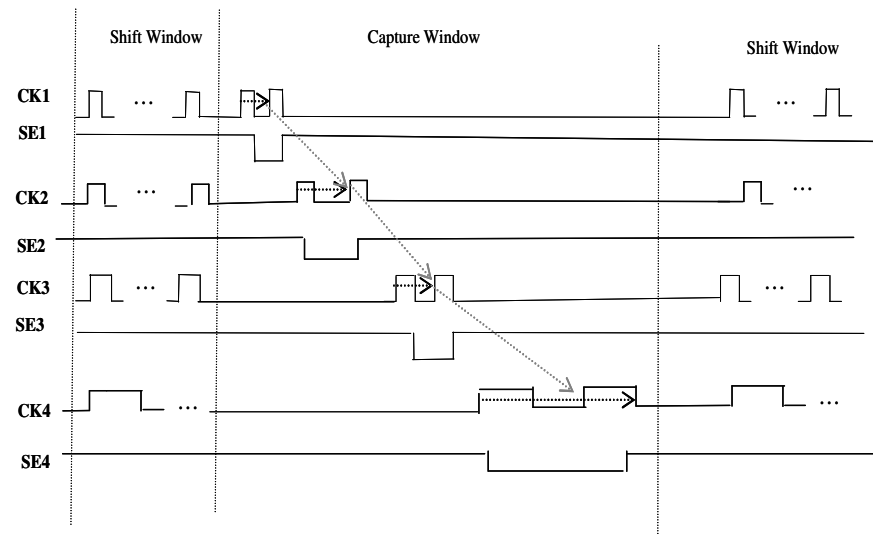


Aligned double-capture - I:

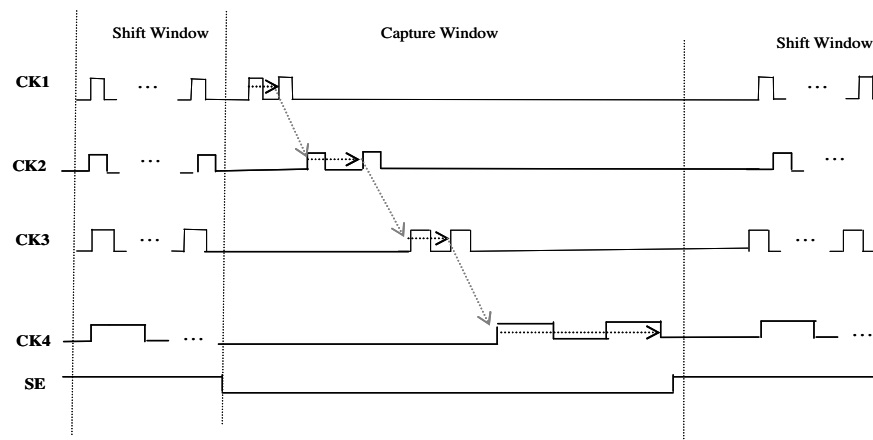


## 5.19

Staggered skewed-load:



Staggered double-capture:



## 5.20

Hybrid double-capture:

